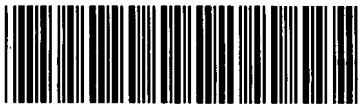


## **Search Notes**



**Application/Control No.**

10/540,354

Examiner

EDMUND H. LEE

**Applicant(s)/Patent under  
Reexamination**

SEVIGNY ET AL.

## **Art Unit**

1732

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner